



---

**FINAL PRODUCT/PROCESS CHANGE NOTIFICATION #16363B**

Generic Copy

---

**Issue Date:** 22-Feb-2011

**TITLE:** ON OSPI (ON Semiconductor Philippines Inc) Consolidation from Calamba, Philippines to Carmona, Philippines.

**PROPOSED FIRST SHIP DATE:** Starting from Q2-2011

**AFFECTED CHANGE CATEGORY(S):** Major with no change in fit, form or function

**FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:**

Contact your local ON Semiconductor Sales Office or <[OSPI.Onesitequality@onsemi.com](mailto:OSPI.Onesitequality@onsemi.com)>

**SAMPLES:** Contact your local ON Semiconductor Sales Office

**ADDITIONAL RELIABILITY DATA:** Available

Contact your local ON Semiconductor Sales Office or <[OSPI.Onesitequality@onsemi.com](mailto:OSPI.Onesitequality@onsemi.com)>

**NOTIFICATION TYPE:**

Final Product/Process Change Notification (FPCN)

Final change notification sent to customers. FPCNs are issued at least 90 days prior to implementation of the change.

ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact <[quality@onsemi.com](mailto:quality@onsemi.com)>.

**DESCRIPTION AND PURPOSE:**

Due to the consolidation of OSPI under a single site in Carmona, Philippines, following operations will be moved:

Incoming quality inspection

Wafer test

Electrical final test/quality control

Mechanical test

Mechanical finishing

Outgoing quality inspection/packing



**FINAL PRODUCT/PROCESS CHANGE NOTIFICATION #16363B**

**QUALIFICATION PLAN:**

**Backend flow - Control plan**

The content and sequence of the processes and the operations in the control plan are not changed.

**Release and acceptance process**

***Calibration and verification of related hardware***

Successful verification of the transferred hardware

***Release procedure.***

Device test

A full parametric correlation, on 2 products that cover all tester resources. As these 2 products were correlated all other products that were previously released on this tester for device test are released too.

Wafer sort

A full parametric correlation, on 2 products that cover all tester resources. As these 2 products were correlated all other products that were previously released on this tester for wafer test are released too.

Successful correlation of the system. Reports can be provided on customer request.